BUK752R3-40C

Rev. 03 — 26 January 2009

Product data sheet

1. Product profile

1.1 General description

Standard level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Avalanche robust

- Suitable for standard level gate drive
- Suitable for thermally demanding environment up to 175°C rating

1.3 Applications

- 12V Motor, lamp and solenoid loads
- High performance automotive power systems
- High performance Pulse Width Modulation applications

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		- =	- 11	40	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1] [2]	W	N.07	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	333	W
Dynamic	characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 32 \text{ V}; \text{ see } \frac{\text{Figure 15}}{\text{ Figure 15}}$		-	67	-	nC
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{Figure } 13};$ see Figure 13		-	1.96	2.3	mΩ
Avalanc	he ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$I_D = 100 \text{ A}; V_{sup} \le 40 \text{ V};$ $R_{GS} = 50 \Omega; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 \text{ °C}; unclamped$	٧	i vil '	18 . D. I	1.2	J

^[1] Refer to document 9397 750 12572 for further information.

^[2] Continuous current is limited by package.





N-channel TrenchMOS standard level FET

查询BUK752R3-40C供应商

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	D
3	S	source		$G \longrightarrow \overline{A}$
mb	D	mounting base; connected to drain	3-lead TO-220AB; SC-46; SFM3)	mbb076 S

3. Ordering information

Table 3. Ordering information

Type number	Package						
	Name	Description	Version				
BUK752R3-40C	3-lead TO-220AB; SC-46; SFM3	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A				

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	40	V
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	40	V
V_{GS}	gate-source voltage			-20	20	V
I_D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1][2]	-	100	Α
		$T_{mb} = 100 ^{\circ}\text{C}; V_{GS} = 10 \text{V}; \text{see} \underline{\text{Figure 1}};$	[1][2]	-	100	Α
		T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ; see <u>Figure 3</u> ;	[1][3]	-	276	Α
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \mu s$; pulsed; see <u>Figure 3</u>		-	1104	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	333	W
T_{stg}	storage temperature			-55	175	°C
T_j	junction temperature			-55	175	°C
Source-dra	nin diode					
Is	source current	$T_{mb} = 25 ^{\circ}C;$	[1][3]	-	276	Α
		$T_{mb} = 25 ^{\circ}C;$	[1][2]	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	1104	Α
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 100 A; V_{sup} ≤ 40 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	1.2	J
E _{DS(AL)R}	repetitive drain-source avalanche energy	see Figure 4;	[4][5] [6][7]	-	-	J

- [1] Refer to document 9397 750 12572 for further information.
- [2] Continuous current is limited by package.
- [3] Current is limited by chip power dissipation rating.
- [4] Maximum value not quoted. Repetitive rating defined in avalanche rating figure.
- [5] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.
- Repetitive avalanche rating limited by an average junction temperature of 170 °C.
- [7] Refer to application note AN10273 for further information.

4 of 14

查询BUK752R3-40C供应商

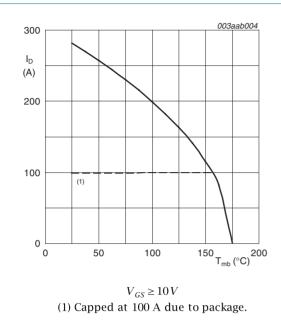


Fig 1. Continuous drain current as a function of mounting base temperature

Product data sheet

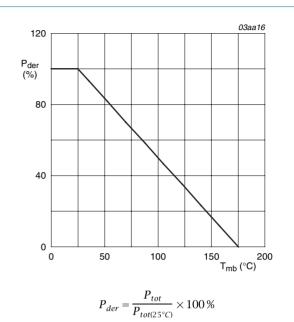
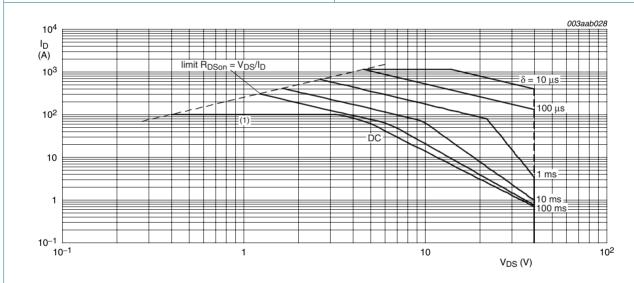


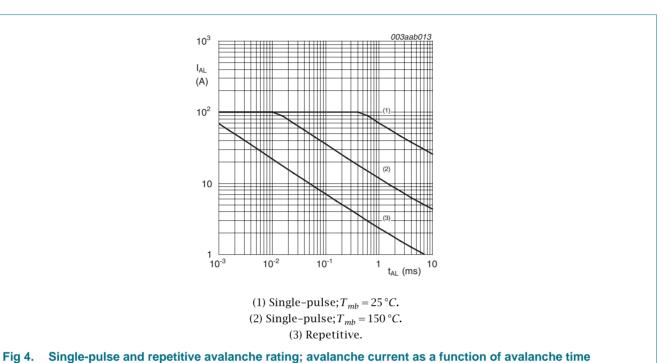
Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse. (1) Capped at 100 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

N-channel TrenchMOS standard level FET



6 of 14

N-channel TrenchMOS standard level FET

查询BUK752R3-40C供应商

Thermal characteristics 5.

Thermal characteristics Table 5.

Product data sheet

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 5	-	-	0.45	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	Vertical in free air	-	60	-	K/W

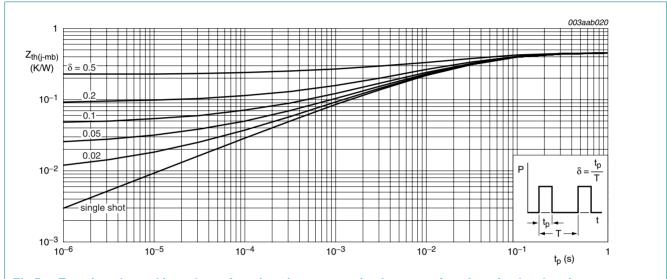


Fig 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	40	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	36	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see Figure 10; see Figure 11	2	3	4	V
V_{GSth}	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = -55 °C; see Figure 10; see Figure 11	-	-	4.4	V
		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 175 °C; see Figure 10; see Figure 11	1	-	-	V
DSS	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
lgss	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		V _{DS} = 0 V; V _{GS} = -20 V; T _i = 25 °C	-	2	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 175 ^{\circ}\text{C}; \text{ see}$ Figure 12; see Figure 13	-	-	4.26	mΩ
		$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 12; see Figure 13	-	1.96	2.3	mΩ
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 25 \text{ A}$; $V_{DS} = 32 \text{ V}$; $V_{GS} = 10 \text{ V}$; see	-	175	-	nC
Q_{GS}	gate-source charge	Figure 15	-	49	-	nC
Q_{GD}	gate-drain charge		-	67	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; \text{ see } \underline{\text{Figure 15}}$	-	5	-	V
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	8492	11323	pF
Coss	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	1606	1927	рF
C _{rss}	reverse transfer capacitance		-	1101	1508	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	65	-	ns
r	rise time	$R_{G(ext)} = 10 \Omega$	-	133	-	ns
d(off)	turn-off delay time		-	146	-	ns
if	fall time		-	119	-	ns
-D	internal drain inductance	from drain lead 6 mm from package to centre of die	-	4.5	-	nΗ
		from contact screw on mounting base to centre of die	-	3.5	-	nΗ
-S	internal source inductance	from source lead to source bonding pad	-	7.5	-	nΗ
Source-d	rain diode					
V _{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 14	-	0.85	1.2	V
rr	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	75	-	ns
		$V_{DS} = 30 \text{ V}$				

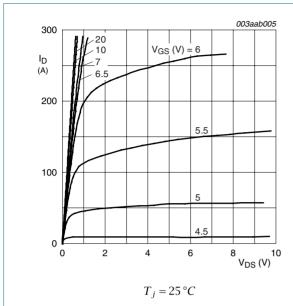


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

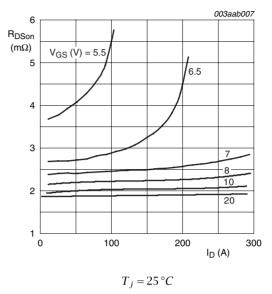


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

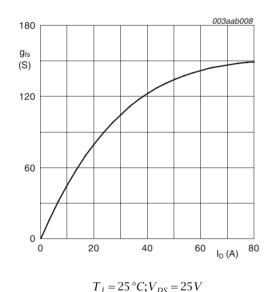


Fig 8. Forward transconductance as a function of drain current; typical values

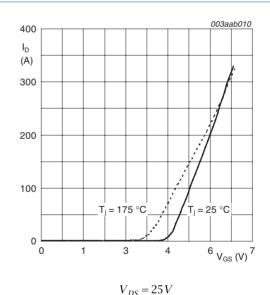
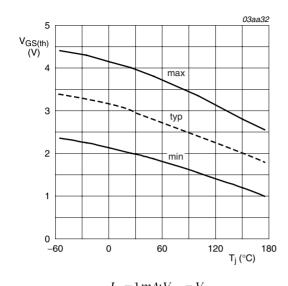
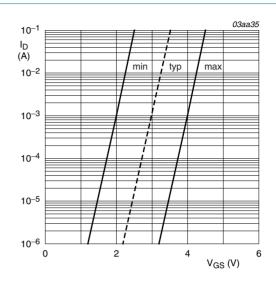


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values



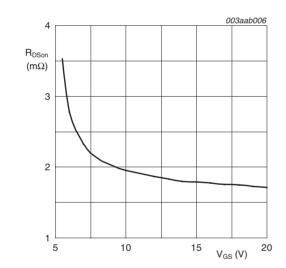
 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 10. Gate-source threshold voltage as a function of junction temperature



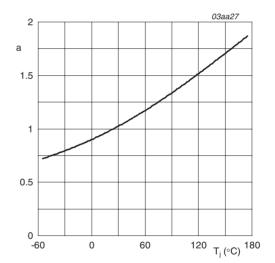
$$T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$$

Fig 11. Sub-threshold drain current as a function of gate-source voltage



 $T_j = 25 \, ^{\circ}C; I_D = 25 \, A$

Fig 12. Drain-source on-state resistance as a function of gate-source voltage; typical values



$$a = \frac{R_{DSon}}{R_{DSon(2.5^{\circ}C)}}$$

Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

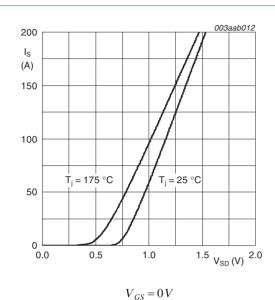
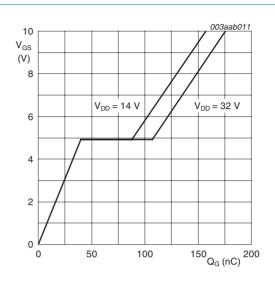
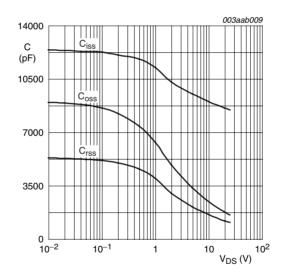


Fig 14. Source current as a function of source-drain voltage; typical values



 $T_j = 25 \,^{\circ}C; I_D = 25A$

Fig 15. Gate-source voltage as a function of gate charge; typical values



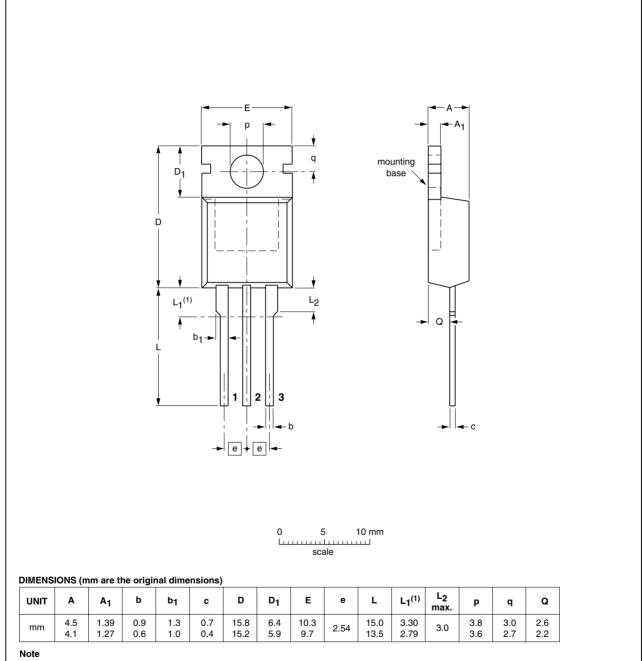
 $V_{GS} = 0V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB

SOT78A



1. Terminals in this zone are not tinned.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78A		3-lead TO-220AB	SC-46		03-01-22 05-03-14

Fig 17. Package outline SOT78A (3-lead TO-220AB; SC-46; SFM3)

12 of 14

查询BUK752R3-40C供应商

N-channel TrenchMOS standard level FET

Revision history

Table 7. **Revision history**

Product data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK752R3-40C_3	20090126	Product data sheet	-	BUK75_7E2R3-40C_2
Modifications:		of this data sheet has bee of NXP Semiconductors.	n redesigned to comply w	rith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Type numb 	er BUK752R3-40C separa	ted from data sheet BUK	75_7E2R3-40C_2.
	 Package or 	utline updated.		
BUK75_7E2R3-40C_2	20060810	Product data sheet	-	BUK75_7E2R3-40C_1
BUK75_7E2R3-40C_1	20060503	Product data sheet	-	-

N-channel TrenchMOS standard level FET

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

9.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

9.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Quick reference data — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at http://www.nxp.com/profile/terms, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

10. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

BUK752R3-40C

查询BUK752R3-40C供应商

N-channel TrenchMOS standard level FET

11. Contents

1	Product profile
1.1	General description1
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information
4	Limiting values3
5	Thermal characteristics6
6	Characteristics7
7	Package outline
8	Revision history12
9	Legal information13
9.1	Data sheet status
9.2	Definitions13
9.3	Disclaimers
9.4	Trademarks13
10	Contact information13

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.



All rights reserved.



founded by